

12. Acknowledgments

First of all, I would like to thank to my supervisor Dr. W. E. S. Unger (Federal Institute of Material Research and Testing (BAM), Laboratory VIII.23) for his excellent supervision, guidance, help and patience during the course and preparation of this thesis.

I would like to give my special thanks to Prof. Dr. M. Hennecke (President of the BAM) for his supervision and Prof. Dr. H. Baumgärtel (Free University Berlin, Institute of Chemistry) for being the referee.

Thanks are due to Mr. T. Wirth for his technical supervision on ToF-SIMS instrument and Dr. I. Retzko for her guidance. Thanks also to all members of Laboratory VIII.23 in BAM for the kindly working atmosphere.

Many thanks to Prof. Dr. J. F. Friedrich (BAM, Laboratory VI.3) for the valuable discussions. Thanks are also due to Dr. R. D. Schulze (BAM, Laboratory VI.3) for his help during setting up the plasma experiment at the ToF-SIMS instrument.

I would like to also thank to Prof. P. Bertrand (Universite catholique de Louven (UCL), Chairman of the Unit of Physical Chemistry and Physics of Materials (PCPM), Belgium), Dr. A. Delcorte (UCL, PCPM), and the members of PCPM in UCL for hosting and helpful discussions on interpretation of SSIMS spectra.

I kindly acknowledge the financial support of the BAM presidency by the “BAM Doktoranden-Programm”.

Special thanks goes to my wife, my family, and my friends for their moral support during this work.